

Directed Testing of ORAN using a Partially Specified Declarative Digital Twin

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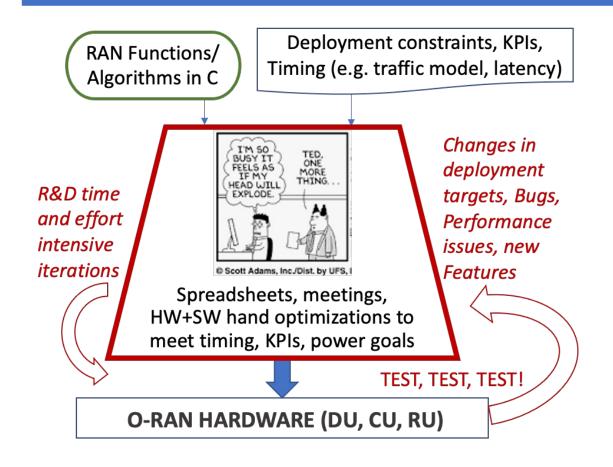
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Real time System Performance of RAN





A competitive high-availability (HA) RAN is a finely tuned real time system, operating near its capacity

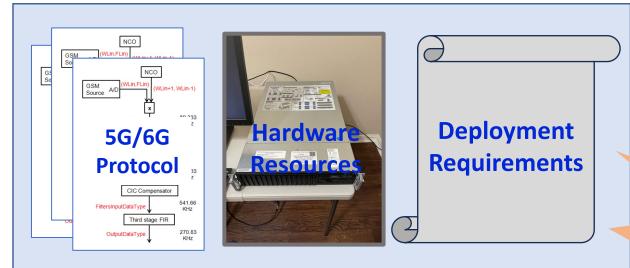
Any mistiming of the hardware or software can lead to unexpected, hard-to-track, functional errors, e.g., buffer overflows, timing errors

Impacts energy efficiency AND performance

→ Requires automation, to direct testing towards specific HW/SW implementation & target deployment. But, not addressed by current open RAN testing strategies

Why is Real Time System Testing Hard?



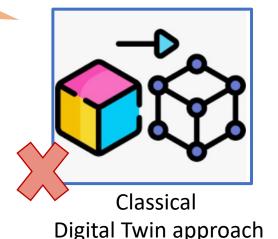


Complexities:

COTS HW/ cRAN/ vRAN,
multivendor,
partial knowledge,
deployment optimized solutions

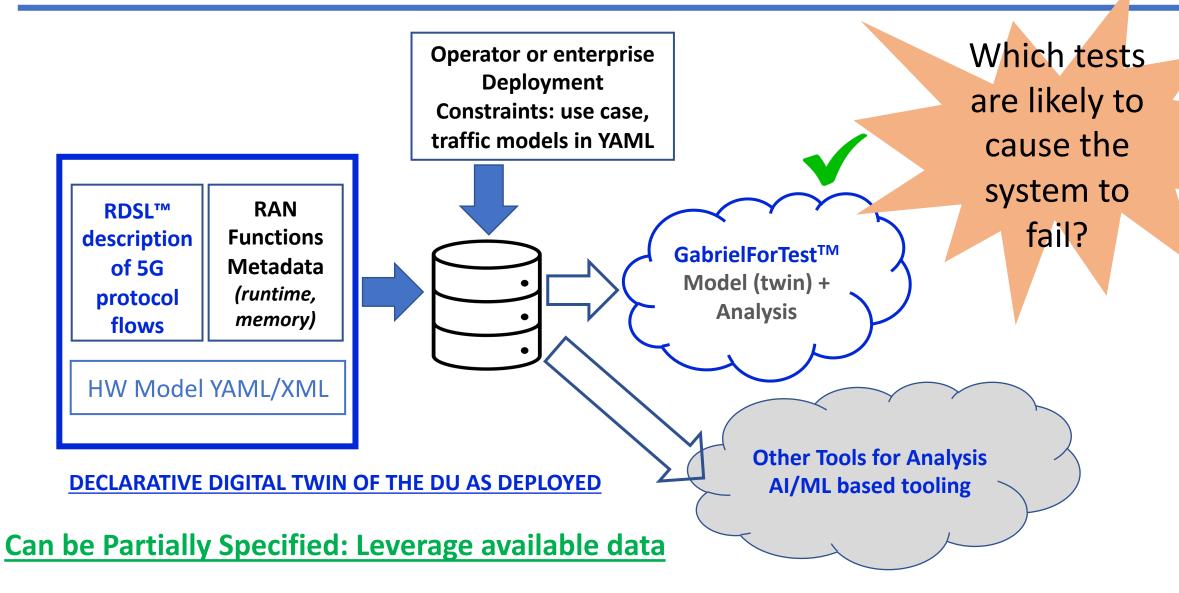
Which tests are likely to cause the system to fail?





A Declarative Digital Twin, powered by a RAN Domain Specific Language





Domain Specific Language (RDSL™): At the heart of the Declarative Digital Twin

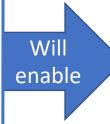


RDSL

(.rdsl, Augmented with .yaml, .xml)

- Separate hardware and implementation independent description
- Declarative, Intent based → adding new requirements does not break the "twin"
- No vendor IP exposure
- Extensible, to meet future needs

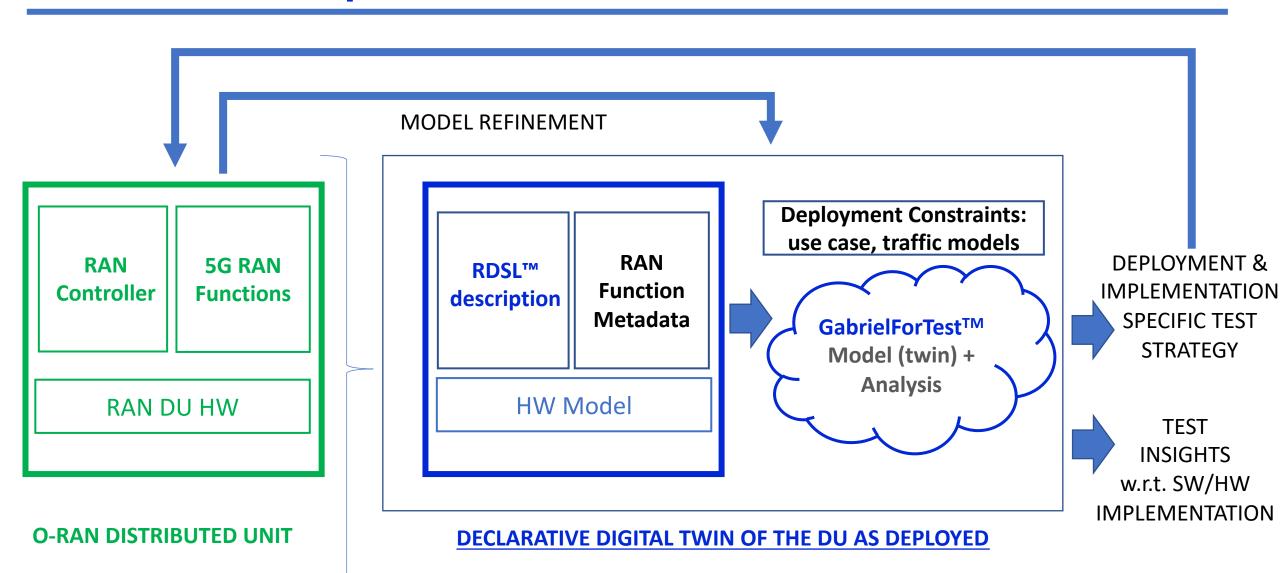
- Simpler and formalized specification
- Automation of testing / digital twins
- ALSO:



- Automation of multi-vendor RAN integration
- Enable RIC apps by automating addition of KPIs
- Integrates smoothly with higherlevel automation and control

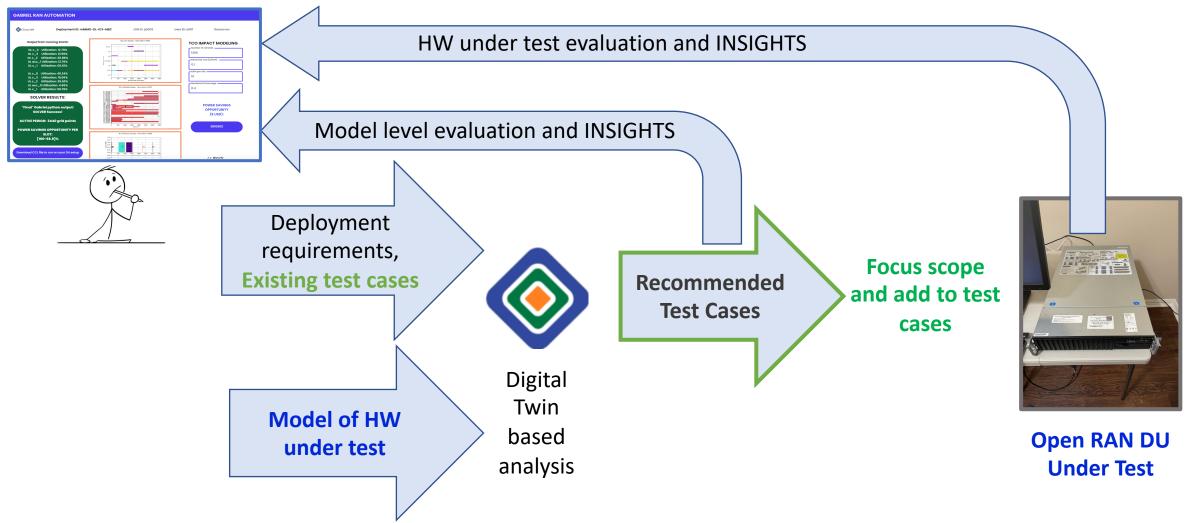
A Declarative Digital Twin Approach to Testing Multi-vendor Open RAN Solutions





How Cirrus360's Declarative Digital Twin works with industry standard testing solutions





Example input to the Declarative Digital Twin: How to test for Cache Sensitivity of DU running on COTS HW



```
: stream[MAX_NUM_RX_ANT]{type = in}
srsIQSymbols
                          stream[AVG_NUM_SRS_UE]{type = in} % Maximum Number of UEs in a given SRS bandwidth
ueSpecific_srsInfo
                          stream[AVG_NUM_SRS_UE][MAX_NUM_RX_ANT][3]
error_streams_type1
                          stream[AVG NUM SRS UE][2]
error_streams_type2
%Internal Stream Definitions
                          stream[AVG_NUM_SRS_UE][MAX_NUM_RX_ANT]% These streams goes to non-RDSL domain
perUE srsChEst
%Flows Multi-instantiation of UE specific SRS Chest Flows for each Symbols
srsChestProc_perUE_perRxAnt_flow{i = 1:AVG_NUM_SRS_UE, j = 1:MAX_NUM_RX_ANT,
                                      srsIQSymbols_perRxAnt_in = srsIQSymbols[j],
                                      perUE_srsInfo_in = ueSpecific_srsInfo[i],
                                      perUE_srsChEst_out = perUE_srsChEst[i][j],
                                      error_s = error_streams_type1[i][j]}
             description of DU Test Case: 10MHz Downlink-only
 Based on fintel@iFlexRANTMReference Architecture
sendSrsChEst_to_MAC_flow{i = 1:AVG_NUM_SRS_UE,
                          perUE_srsChest_in = perUE_srsChEst[i],
                          perUE_srsInfo_in = ueSpecific_srsInfo[i],
                          error_s = error_streams_type2[i]}
```

```
apiVersion: rdsl/v0
kind: timing equation
metadata:
System=Constraints:
Speciming <= A*370 + B < 500
C: grid_period
A: num_ue1
B: gp_base
unit: clock
```

flow srsChest_ueSpecific

```
r<pattern name="big_delay.c_0.L3_0.DDR_0.L3_0">
  <defining memory>L3 0</defining memory>
  <observing memory>L3 0</observing memory>
▼<exclusive define with>
   <member>big delay.c 0.L3 0.DDR 0.L3 0</member>
   <member>big delay.c 0.L3 0.DDR 0.accL3 0</member>
   <member>pipeline.c 0.L3 0</member>
   <member>L2toL2.c 0.L3 0.accL3 0</member>
 </exclusive define with>
▶ <shares L2 II with>
 </shares L2 II with>
▶ <shares L2 I0 with>
 </shares L2 I0 with>
▶ <shares L2 OI with>
 </shares L2 OI with>
▼<shares L2 00 with>
   <member>big_delay.c_0.L3_0.DDR_0.L3_0
   <member>big delay.c 0.L3 0.DDR 0.accL3 0
   <member>L2toL2.c 0.L3 0.accL3 0</member>
   <member>big delay.c 1.L3 0.DDR 0.L3 0</member>
   <member>big delay.c 1.L3 0.DDR 0.accL3 0
   <member>L2toL2.c 1.L3 0.accL3 0</member>
   <member>big delay.c 2.L3 0.DDR 0.L3 0</member>
   <member>big delay.c 2.L3 0.DDR 0.accL3 0
   <member>L2toL2.c 2.L3 0.accL3 0/member>
   <member>big delay.c 3.L3 0.DDR 0.L3 0
   <member>big delay.c 3.L3 0.DDR 0.accL3 0</member>
   <member>L2toL2.c 3.L3 0.accL3 0/member>
 </shares L2 00 with>
 <shares L3 II with/>
 <shares L3 I0 with/>
 <shares L3 OI with/>
 <shares L3 00 with/>
▶ <can observe>
 </can observe>
```

```
apiVersion: rdsl/v0
ind: SDK
 name: NR5G1_DL_PDSCH_SYM
 available patterns:
  big_delay.c_0.L3_0.DDR_0.L3_0
  big_delay.c_0.L3_0.DDR_0.accL3_0
  big_delay.c_2.L3_0.DDR_0.accL3_0
  pipeline.c_2.L3_0
  L2toL2.c_2.L3_0.accL3_0
  big_delay.c_3.L3_0.DDR_0.L3_0
  big_delay.c_3.L3_0.DDR_0.accL3_0
  pipeline.c_3.L3_0
  L2toL2.c_3.L3_0.accL3_0
 elementsize: 2000000
 internalsize: 8000000
 runtime: 7200
```

Cache Sensitivity of DU running on COTS HW: Testing recommendations from Digital Twin



	Strategy	Latency (clock cycles)	Result from GabrielForTest™
1	No added constraints related to cache	207,800	Test can successfully complete on a hardware slice of 4 cores well within available slot time
2	Cache eviction occurs for a set of small buffers (all < 10KB)	239,400 (15% increase)	Small impact, robust to this cache effect
3a	Large shared buffer (DL Config) eviction	420,000 (102% increase)	Big impact! Requires this test scenario to be reproduced on actual DU. May be a candidate for code change to avoid this situation in the field
3b	Large data buffer cache eviction	464,600 (124% increase)	Some additional impact, Digital Twin can explain why!

Table 1: Results for different pattern management (cache sensitivity) constraints: Impact on Latency

Conclusions



- System Performance testing is hard! Takes expertise, R&D time, and effort but essential for multivendor ORAN to be competitive
- RDSL™ driven DECLARATIVE DIGITAL TWIN can accelerate system testing:
 - Large repository of FACTS or CONSTRAINTS about the deployed ORAN component(s)
 - That AUTOMATION can analyze for HW-SW implementation related corner cases
 - Enables directed system testing to accelerate testing time and investment for ORAN

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ADDITIONAL SLIDES

Team





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- Distinguished Member Tech Staff Texas Instruments, Board Member Reliance Jio JV
- MIT Tech Review top innovators (TR35), 13 patent families







ALAN GATHERER (PhD), CTO

- Senior VP, 5G Baseband SoCs, Futurewei/Huawei (10 years rise to market leader)
- IEEE Fellow (1% of members), 90+ patents
- Texas Instruments Fellow, drove TI's domination for >10 years of 3G/4G





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- Founder SNRLabs, acquired by SEVEN. WiFi-cellular mobility product & core IP



Qualconn



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- Virginia Tech, IEEE Fellow (Software Defined Radio)
- Co-founder of Federated Wireless, Advisor US spectrum policies

